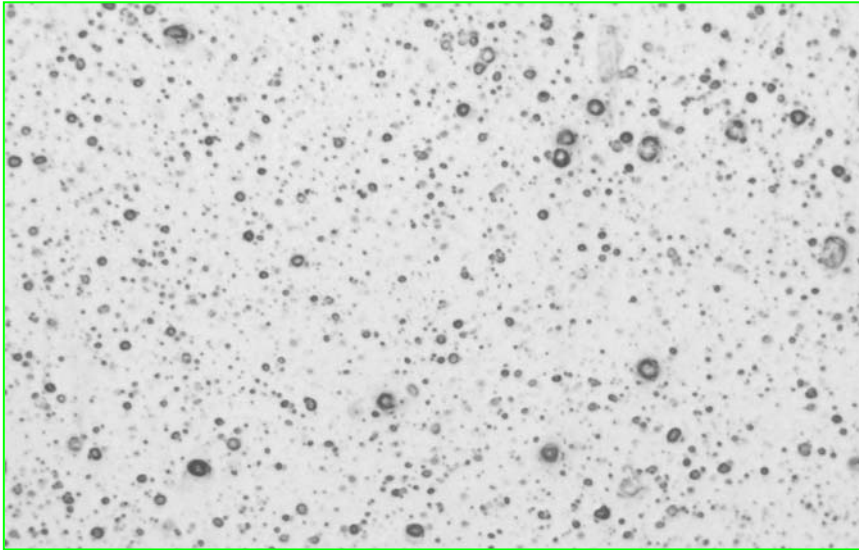


# Particle Sizing Analysis - Run 1

**Date:** 2006-Jan-23, 1:19:48 PM -05'00'  
**Company:** Clemex Technologies Inc.  
**User:** Myriam Savard (signed on 2006-Jan-23 12:38:31 -05'00')  
**Sample ID:** Y

**Magnification:** 200x  
**Calibration:** 0.3375  $\mu\text{m}/\text{pixel}$   
**Units:** microns  
**Count:** 14386

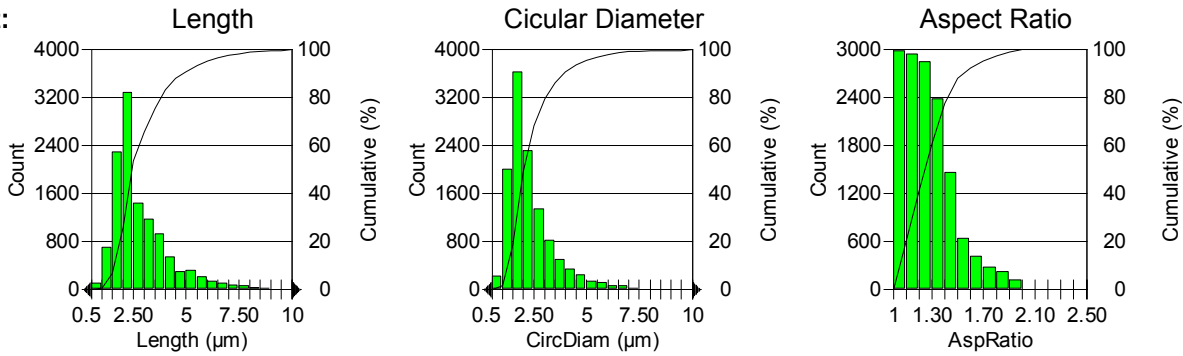
**Figure 1:** Typical field of view.



**Comment:**

The analysis was performed using reflected light. Particles were binarized by gray thresholding. Some artifacts were eliminated prior to measurement. Results can be printed directly from PS3. Their presentation can also be customized using the Report Generator like in the current example.

**Chart:**



<b>Minimum:</b>	0.34	0.38	1.00
<b>Maximum:</b>	16.07	13.90	1.99
<b>Mean:</b>	2.48	2.04	1.27
<b>Std Dev.:</b>	1.70	1.32	0.21
<b>D10:</b>	0.34	0.38	1.00
<b>D50:</b>	2.16	1.82	1.25
<b>D90:</b>	4.51	3.64	1.56

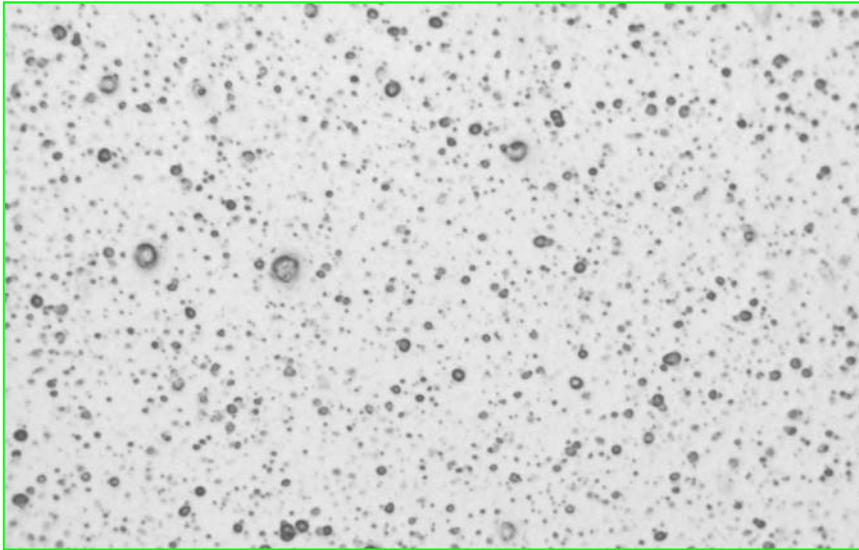
**Approbation:**

# Particle Sizing Analysis - Run 2

**Date:** 2006-Jan-23, 1:25:26 PM -05'00'  
**Company:** Clemex Technologies Inc.  
**User:** Myriam Savard (signed on 2006-Jan-23 12:38:31 -05'00')  
**Sample ID:** Y

**Magnification:** 200x  
**Calibration:** 0.3375  $\mu\text{m}/\text{pixel}$   
**Units:** microns  
**Count:** 14158

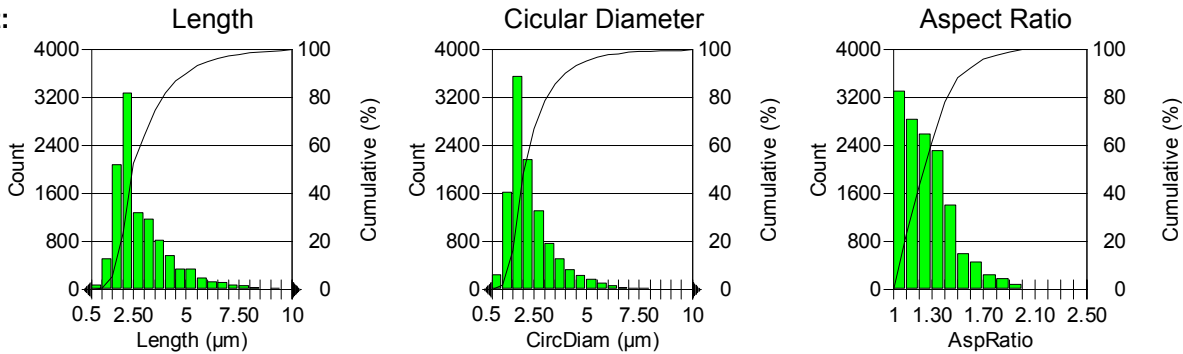
**Figure 1:** Typical field of view.



**Comment:**

The analysis was performed using reflected light. Particles were binarized by gray thresholding. Some artifacts were eliminated prior to measurement. Results can be printed directly from PS3. Their presentation can also be customized using the Report Generator like in the current example.

**Chart:**



<b>Minimum:</b>	0.34	0.38	1.00
<b>Maximum:</b>	16.37	13.54	1.98
<b>Mean:</b>	2.46	2.02	1.27
<b>Std Dev.:</b>	1.79	1.39	0.21
<b>D10:</b>	0.34	0.38	1.00
<b>D50:</b>	2.15	1.80	1.24
<b>D90:</b>	4.63	3.70	1.55

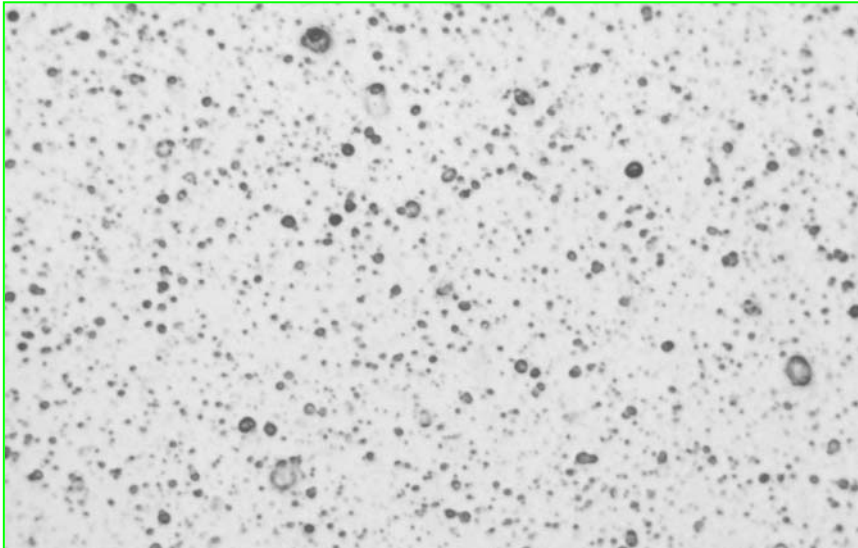
**Approbation:**

# Particle Sizing Analysis - Run 3

**Date:** 2006-Jan-23, 1:31:47 PM -05'00'  
**Company:** Clemex Technologies Inc.  
**User:** Myriam Savard (signed on 2006-Jan-23 12:38:31 -05'00')  
**Sample ID:** Y

**Magnification:** 200x  
**Calibration:** 0.3375  $\mu\text{m}/\text{pixel}$   
**Units:** microns  
**Count:** 14044

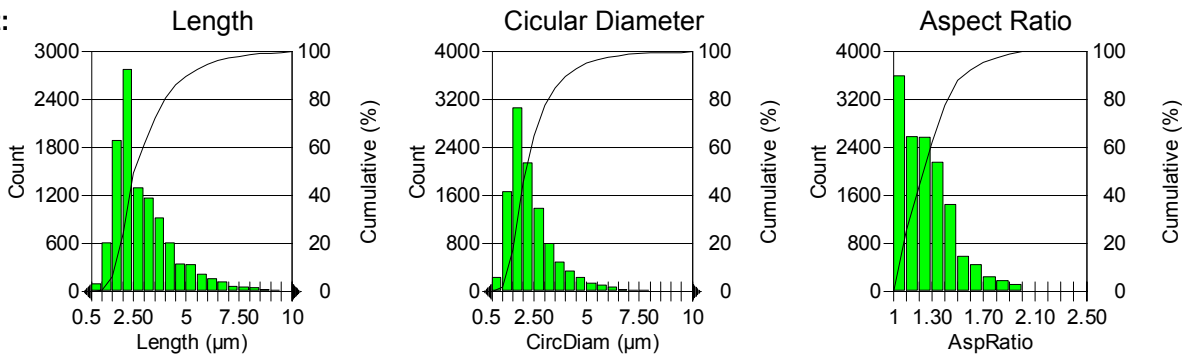
**Figure 1:** Typical field of view.



**Comment:**

The analysis was performed using reflected light. Particles were binarized by gray thresholding. Some artifacts were eliminated prior to measurement. Results can be printed directly from PS3. Their presentation can also be customized using the Report Generator like in the current example.

**Chart:**



<b>Minimum:</b>	0.34	0.38	1.00
<b>Maximum:</b>	19.95	16.73	1.99
<b>Mean:</b>	2.44	2.00	1.26
<b>Std Dev.:</b>	1.84	1.43	0.21
<b>D10:</b>	0.34	0.38	1.00
<b>D50:</b>	2.13	1.79	1.24
<b>D90:</b>	4.69	3.70	1.55

**Approbation:**

# Binarization of Typical Field

Figure 1: Part of the original image at 200x (0.3375 micron/pixel).

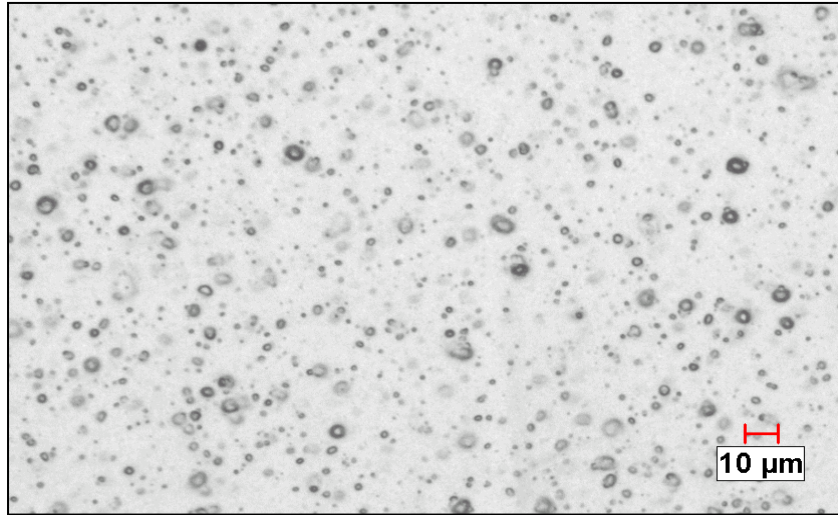


Figure 2: Binarized particles as measured.

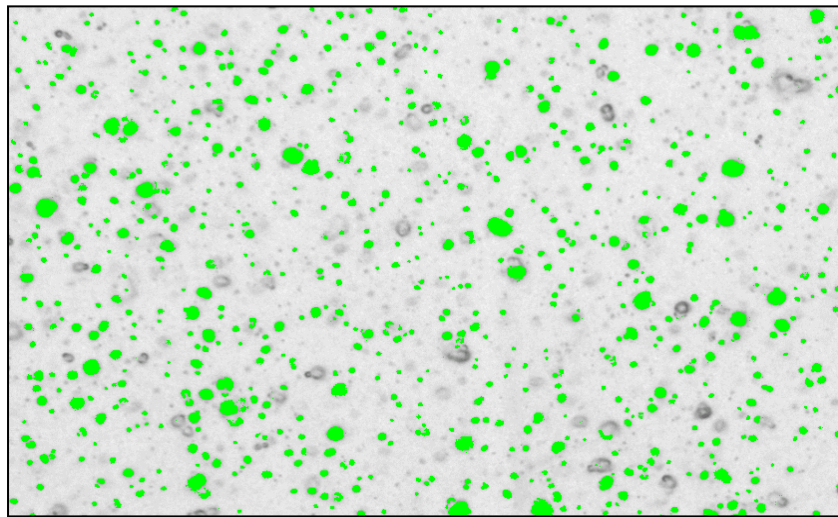


Figure 3: Same as previous but in outline view.

